

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Date: Ju

July 5, 2001 🖅

B.S. Beaman et al.

Group Art Unit: 2858

Serial No.: 09/251,988

Examiner: Jermele M. Hollington

Filed: February 17, 1999

Docket No.: YO999-088

For:

Structural Design And Processes To Control Probe Position Accuracy

In A Wafer Test Probe Assembly

Assistant Commissioner for Patents Washington, D.C. 20231

#### PETITION FOR CORRECTED FILING RECEIPT

Sir:

Applicants petition for correcting the filing receipt to state: "This application is a Continuation-in-part of co-pending Application Serial No. 09/088,394 filed on June 1, 1998, which is a Divisional Application of US Application 08/754,869 filed on November 22, 1996 now issued as US Patent 5,821,763, which is a Continuation of US Application No. 08/055,485 filed on April 30, 1993 now issued as US Patent 5,635,846."

Please charge any fee necessary to enter this paper to deposit account 09-0468.

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Respectfully submitted,

Dr. Daniel P. Morris

Reg. No. 32,053 (914) 945-3217

IBM Corporation Intellectual Property Law Dept. P.O. Box 218 Yorktown Heights, New York 10598

Serial No.: 09/251,988

Docket No. YO999-088



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Rih Data Sheet

**CONFIRMATION NO. 3930** 

Bib Data Sheet										
SERIAL NUMBE 09/251,988	. 02/1//1000		CLASS 324		GROUP ART UNIT 2858		UNIT	ATTORNEY DOCKET NO. Y0998-088		
APPLICANTS		DEAMAN AREV NO								
BRIAN SAMUEL BEAMAN, APEX, NC; KEITH E. FOGEL, MOHEGAN LAKE, NY; PAUL A. LAURO, NANUET, NY; SANG HYON PAEK, NEW YORK, NY; DA-YUAN SHIH, POUGHKEEPSIE, NY;						RECENTER				
** CONTINUING DATA **********************************										
** FOREIGN APPLICATIONS ************************************										
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 05/19/1999										
Foreign Priority claimed  35 USC 119 (a-d) conditions  met  Verified and Acknowledged  yes  no  Met after  Allowance  Examiner's Signature  Initials			STATE OR COUNTRY NC	DRAWING CL		CLAI	TOTAL INDEPENDENT CLAIMS CLAIMS 47 3			
ADDRESS	V	V								
IBM CORPORATION										
INTELLECTUAL PROPERTY LAW DEPT P O BOX 218										
YORKTOWN HEIGHTS ,NY 10598										
TITLE STRUCTURAL DI TEST PROBE AS		N AND PROCESSES	TO CON	ITROL PROBE	E POSI	TION A	CCURA	CY IN	A WAFER	
	FEES: Authority has been given in Paper No to charge/credit DEPOSIT No for following:					☐ All Fees				
					r IT ACCOUNT		1.16 Fees (Filing)			
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1376						☐ 1.18 Fees (Issue)				
							Other			
						☐ Credit				

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GAU 2808

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: B. S. Beaman et al.

Docket No.: Y0999-088

Serial No.: 09/251,988

Group No.: 2858

Filed: February 17, 1999

Examiner: J. M. Hollington

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE POSITION

ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Assistant Commissioner for Patents Washington, D.C. 20231

#### CERTIFICATE OF MAILING UNDER 37 CFR 1.8 (a)

I hereby certify that the attached correspondence comprising:

Amendment

Petition For Corrected Filing Receipt
Information Disclosure Statement Transmittal Letter
PTO-1449 Form with 52 References attached
Attachments - PTO Forms 1449 and 803
Return Postcard

is being deposited with the United States Postal Service as first class mail in an envelope addressed to:

Assistant Commissioner for Patents Washington, D.C. 20231.

on <u>July 17, 2001</u>

Jennifer A. Smith

(Type or printed name of person mailing paper or fee)

(Signature of person mailing paper or fee)